

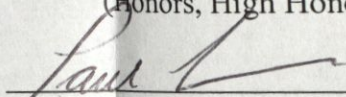
The Test-Retest Reliability of ERP Components as Assessed by the Brief Neurometric Battery

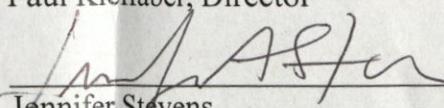
A thesis submitted in partial fulfillment of the requirement
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The College of William and Mary

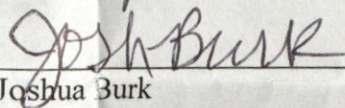
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